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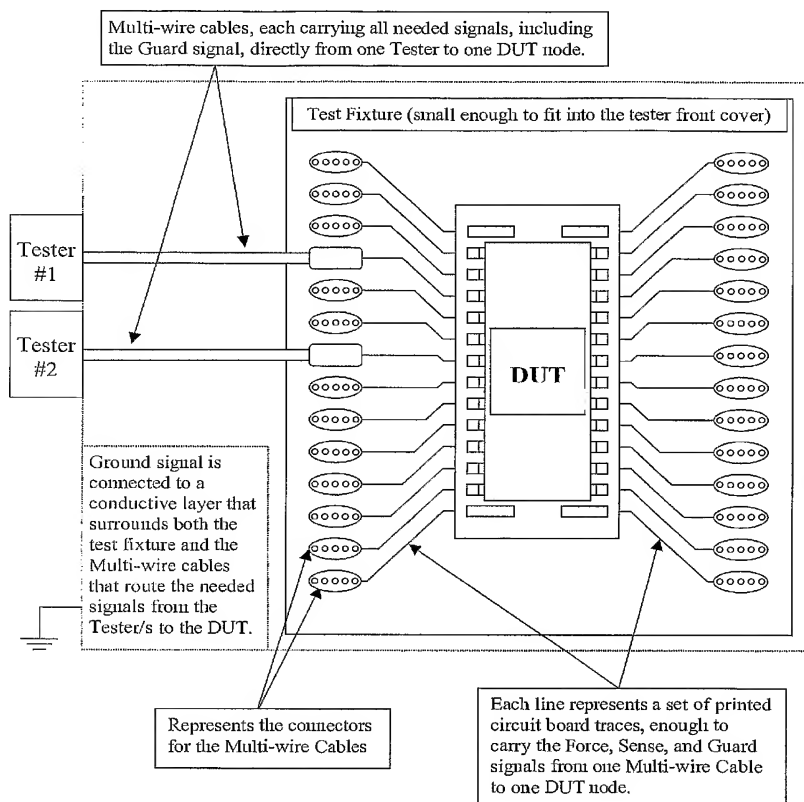
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(54) Title: ELECTRICAL CONNECTOR FOR SEMICONDUCTOR DEVICE TEST FIXTURE AND TEST ASSEMBLY



(57) Abstract: An interconnect assembly is for use in connection a semiconductor device under test (DUT) having a plurality of leads to electronic test equipment. The interconnect assembly includes a cable including a plurality of wires with at least one wire for sensing a signal from a DUT, at least one wire for a forcing signal to the DUT, and at least one wire for a guarding signal driven by the same electrical potential as the forcing signal. A male connector includes the plurality of wires, an outer metal coating surrounding the plurality of wires, and an insulating coating around the outer metal coating. A receptacle connector is for receiving the male connector and plurality of wires with corresponding contacts.



SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

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